


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564085	<b>Applicant(s)/Patent Under Reexamination</b>  SAITOH ET AL.
	<b>Examiner</b>  MEIYA LI	<b>Art Unit</b>  2811

SEARCHED			
Class	Subclass	Date	Examiner
257	565,576,191,197,200,201,E31.043-E31.049		
438	170,172,189,234,235,309,312	7/10/09	ML

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	7/10/09	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner